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 (2003 2 21 , 2003 5 13)

The Variation of Structure and Physical Properties of XLPE during Thermal Aging Process

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(Received February 21, 2003; accepted May 13, 2003)

: 가 가 X- 가
 1715 nm 가 가
 가 TMA, - ,
 가 110 132 가 ,
 265 110% D 32 50 가 .

ABSTRACT : The variation of chemical structure and physical properties of crosslinked polyethylene (XLPE) during thermal aging process was investigated. The formation of carbonyl functional group resulting from thermal oxidation reaction of XLPE was monitored using X-ray photoelectron spectroscopy and near infrared (NIR) spectroscopy. It was observed that the intensity of carbonyl peak observed at 1715 nm linearly increased with aging time in NIR spectroscopy. The linear relationship between NIR peak absorbance and aging time confirmed that NIR spectroscopy might be used as a proper tool for monitoring the aging process of polymeric materials. Also the formation of crosslinks during the aging process was monitored using thermal mechanical analysis, stress-strain test, and Shore hardness test. The change in the physical properties, such as the increase in the glass transition temperature from 110 to 132 , the decrease in the strain from 265 to 110%, as well as the increase in the shore D hardness from 32 to 50, was observed during the aging process.

Keywords : XLPE, thermal aging, NIR, XPS.

1. 14 가

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Systems Inc. Model 6500 Multi Mode Analyzer
 Si detector (400-1100 nm) PbS
 detector (1100-2500 nm) 1 × 1 ×
 0.1 cm
 Foss NIR System VISION 2.22
 (segment
 size 10 nm, gap size 10 nm)
 2
 (multiple linear regression)
 Instron Mechanical
 Tester (Model 4400R) 10 × 1 ×
 0.1 cm
 ASTM D638-99, crosshead speed 10
 mm/min
 ASTM D2240-91
 Teclock Corp. Shore Type D Hardness Tester

3.

XLPE

XLPE

XPS

XPS spectra C_{1s}

Figure 1

XLPE

C_{1s}

3

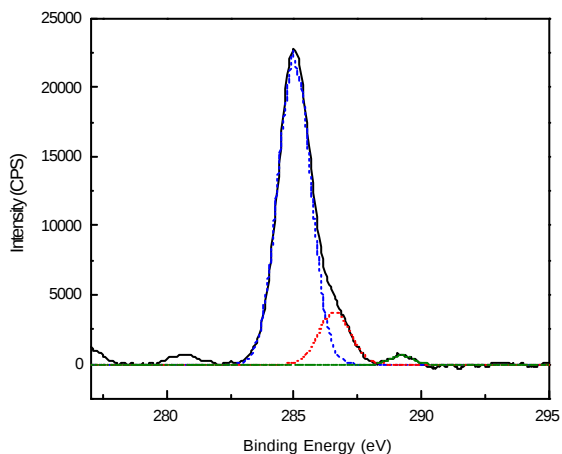


Figure 1. XPS C_{1s} spectra of XLPE film aged for 70 years.

가 XLPE
 curve-fitting

가 14-18 XLPE C_{1s}
 285.0 eV C-C, 286.5 eV C-O
 289.2 eV O-C=O
 18 가 XLPE
 C-O O-C=O 가
 Figure 2 XLPE O-C=
 O/C-C XLPE가
 가
 50
 가 가,
 가 70 7%
 가
 XLPE 가
 XLPE

(Near Infrared
 Spectroscopy, NIRS)

, -C-N=, =N-H, -O-H, -S-H
 780 2500 nm

NIRS 1800 William Herschel

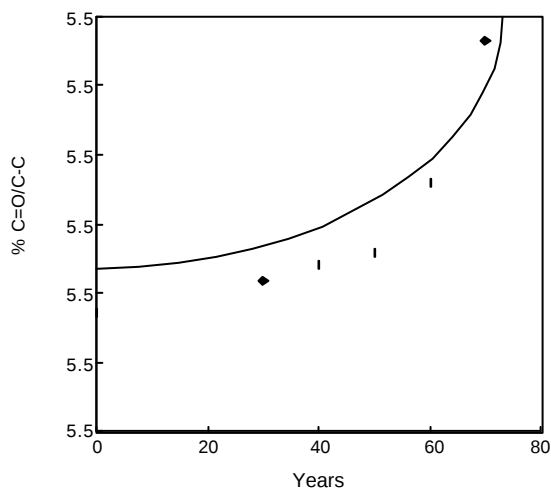


Figure 2. Relative intensity of C=O/C-C peaks in XPS depending on aging time.

1980
(chemometrics)
,
,
(combination)
1000 가
가,
가
25-27
(chemometrics)
가
가
가
(multi-variate)
(MLR, multiple linear regression),
(PCR, principle component regression),
(PLS, partial least square regression)
NIRS
22
NIR-chemometrics
NIR
Figure 3
spectra
가
가
NIR
C-H, OH, N-H, C=O, =C-H,

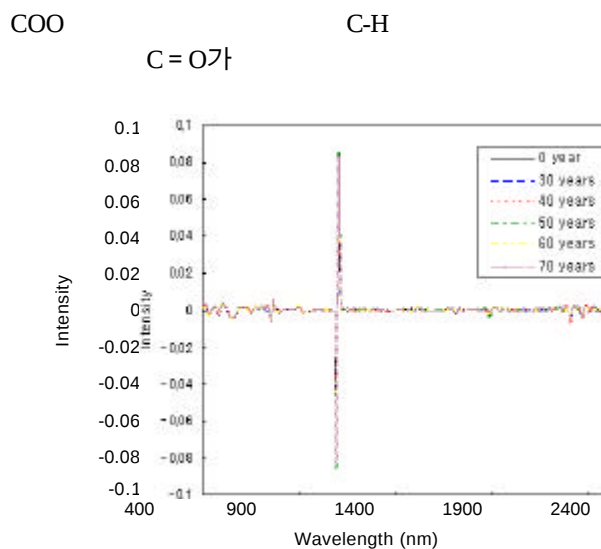


Figure 3. NIR spectra of XLPE film.

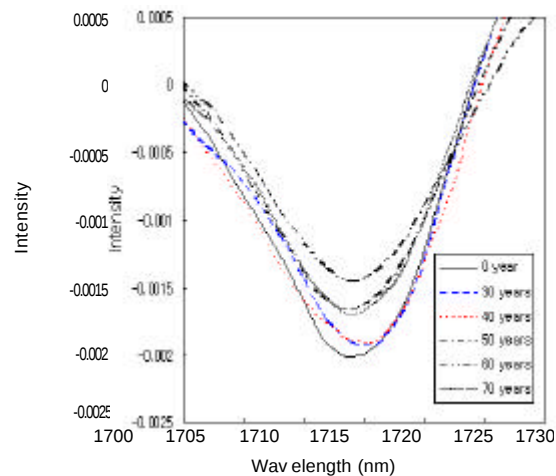


Figure 4. Absorption peak at 1715 nm depending on aging time.

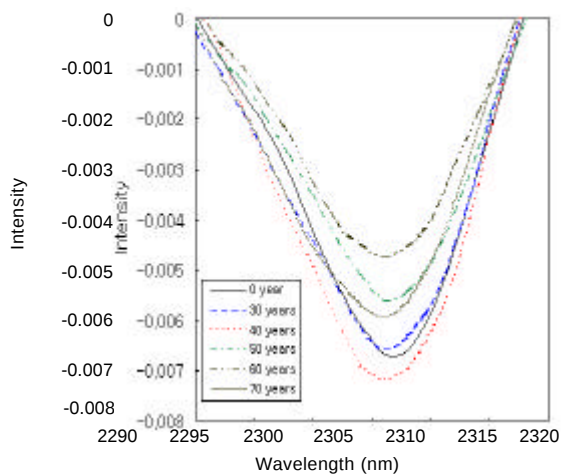


Figure 5. Absorption peak at 2305 nm depending on aging time.

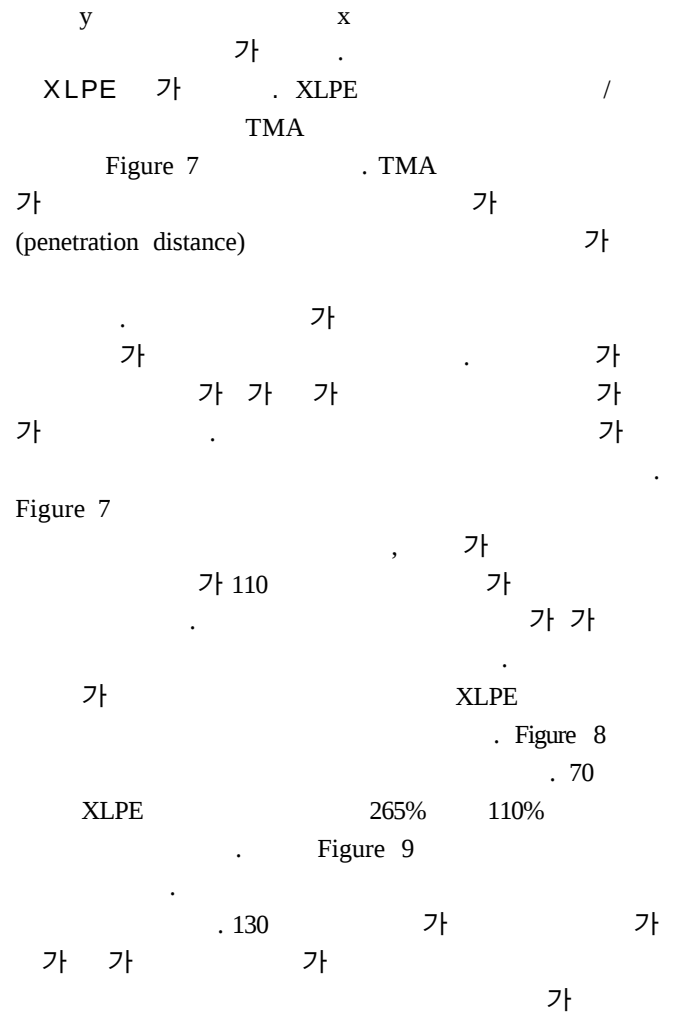
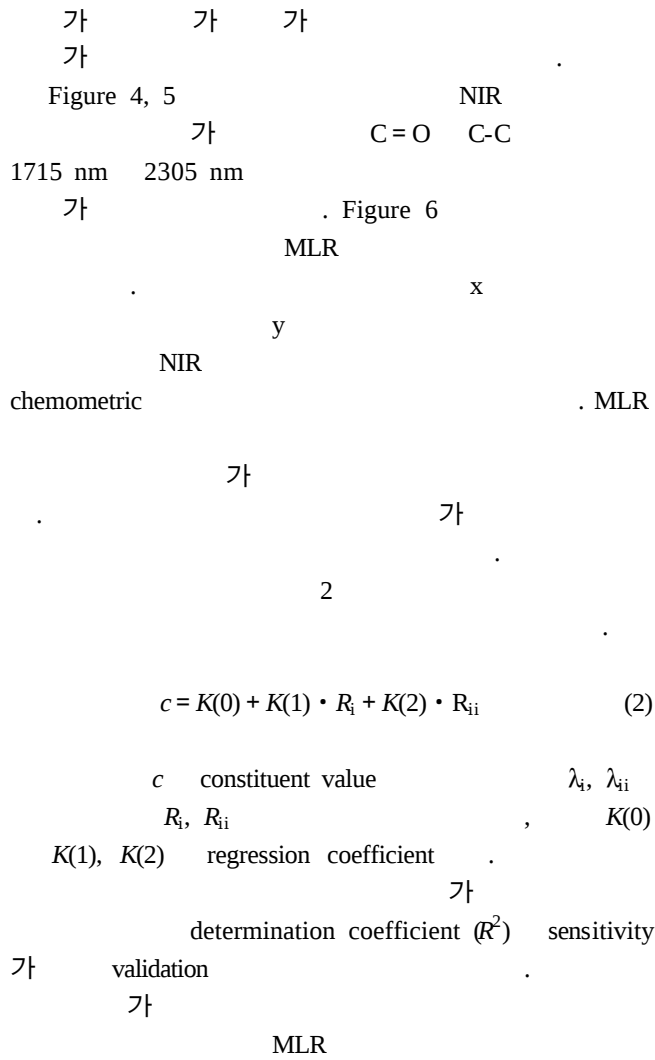


Figure 6. Scatter plot of NIR calibration set depending on aging time.

Figure 7. TMA heating scan of XLPE after aging.

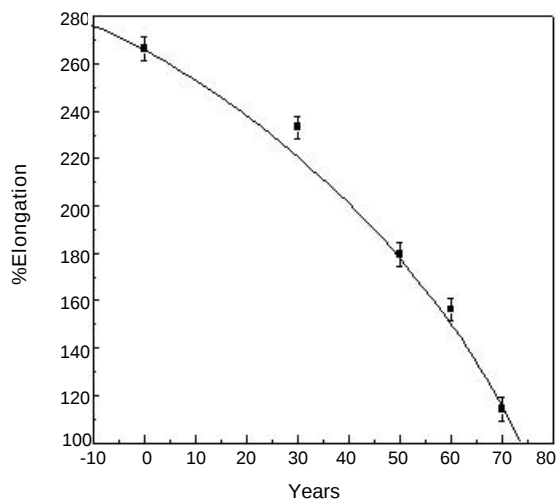


Figure 8. Elongation versus aging time.

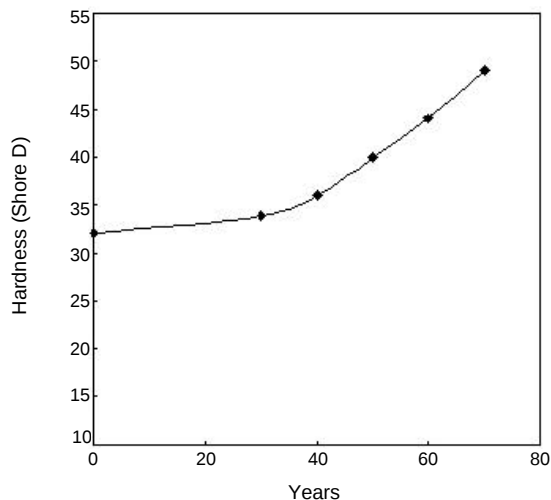


Figure 9. Hardness versus aging time.

4. 가 (XLPE) . XLPE
130 가
가 .
가 .
가 . XPS (289.2 eV) NIR (1715 nm) 가
가 . 가 .
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